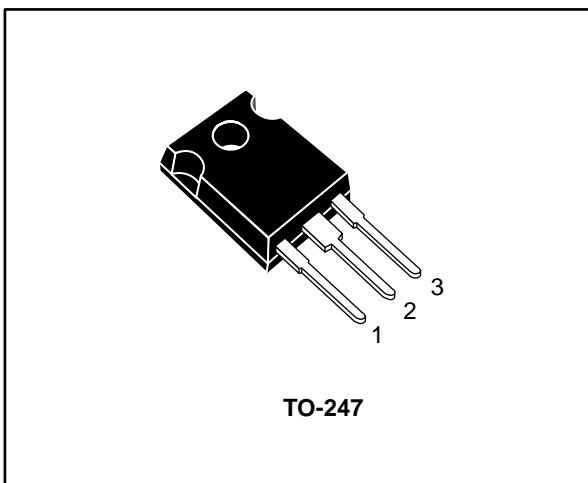
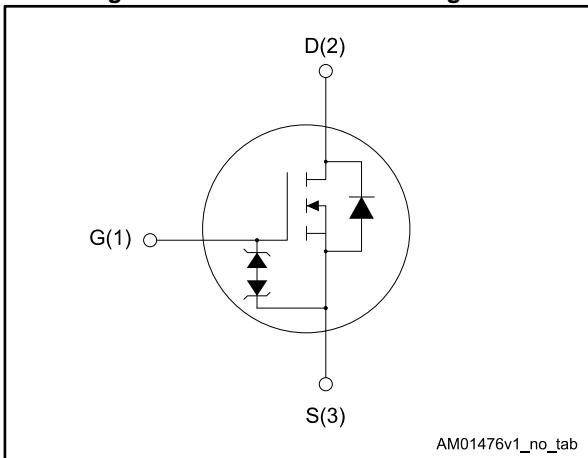


## N-channel 650 V, 0.087 Ω typ., 32 A MDmesh™ M2 Power MOSFET in a TO-247 package

Datasheet - production data



**Figure 1: Internal schematic diagram**



### Features

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STW40N65M2	650 V	0.099 Ω	32 A

- Extremely low gate charge
- Excellent output capacitance (C<sub>oss</sub>) profile
- 100% avalanche tested
- Zener-protected

### Applications

- Switching applications

### Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

**Table 1: Device summary**

Order code	Marking	Package	Packaging
STW40N65M2	40N65M2	TO-247	Tube

**Contents**

<b>1</b>	<b>Electrical ratings .....</b>	<b>3</b>
<b>2</b>	<b>Electrical characteristics .....</b>	<b>4</b>
	2.2    Electrical characteristics (curves).....	6
<b>3</b>	<b>Test circuits .....</b>	<b>8</b>
<b>4</b>	<b>Package information .....</b>	<b>9</b>
	4.1    TO-247 package information.....	9
<b>5</b>	<b>Revision history .....</b>	<b>11</b>

# 1 Electrical ratings

**Table 2: Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	32	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	20	A
$I_{DM}^{(1)}$	Drain current (pulsed)	128	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	250	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15	V/ns
$dv/dt^{(3)}$	MOSFET dv/dt ruggedness	50	V/ns
$T_{stg}$	Storage temperature	- 55 to 150	$^\circ\text{C}$
$T_j$	Max. operating junction temperature	150	

**Notes:**

(1) Pulse width limited by safe operating area.

(2)  $I_{SD} \leq 32$  A,  $dI/dt \leq 400$  A/ $\mu\text{s}$ ;  $V_{DS}$  peak <  $V_{(BR)DSS}$ ,  $V_{DD} = 400$  V(3)  $V_{DS} \leq 520$  V**Table 3: Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	0.5	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	50	$^\circ\text{C}/\text{W}$

**Table 4: Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax}$ )	3	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50$ V)	820	mJ

## 2 Electrical characteristics

( $T_C = 25^\circ\text{C}$  unless otherwise specified)

**Table 5: On/off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	650			V
$I_{\text{DSS}}$	Zero gate voltage Drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}, T_C = 125^\circ\text{C}$			100	$\mu\text{A}$
$I_{GSS}$	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 16 \text{ A}$		0.087	0.099	$\Omega$

**Table 6: Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	2355	-	pF
$C_{oss}$	Output capacitance		-	102	-	pF
$C_{rss}$	Reverse transfer capacitance		-	2.7	-	pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0 \text{ V to } 520 \text{ V}, V_{GS} = 0 \text{ V}$	-	380	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}$ open drain	-	4.5	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 520 \text{ V}, I_D = 32 \text{ A}, V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 15: "Gate charge test circuit"</a> )	-	56.5	-	nC
$Q_{gs}$	Gate-source charge		-	8	-	nC
$Q_{gd}$	Gate-drain charge		-	24	-	nC

**Notes:**

<sup>(1)</sup> $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

**Table 7: Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 325 \text{ V}, I_D = 16 \text{ A}$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 14: "Switching times test circuit for resistive load"</a> and <a href="#">Figure 19: "Switching time waveform"</a> )	-	15	-	ns
$t_r$	Rise time		-	10	-	ns
$t_{d(off)}$	Turn-off-delay time		-	96.5	-	ns
$t_f$	Fall time		-	12	-	ns

Table 8: Source drain diode

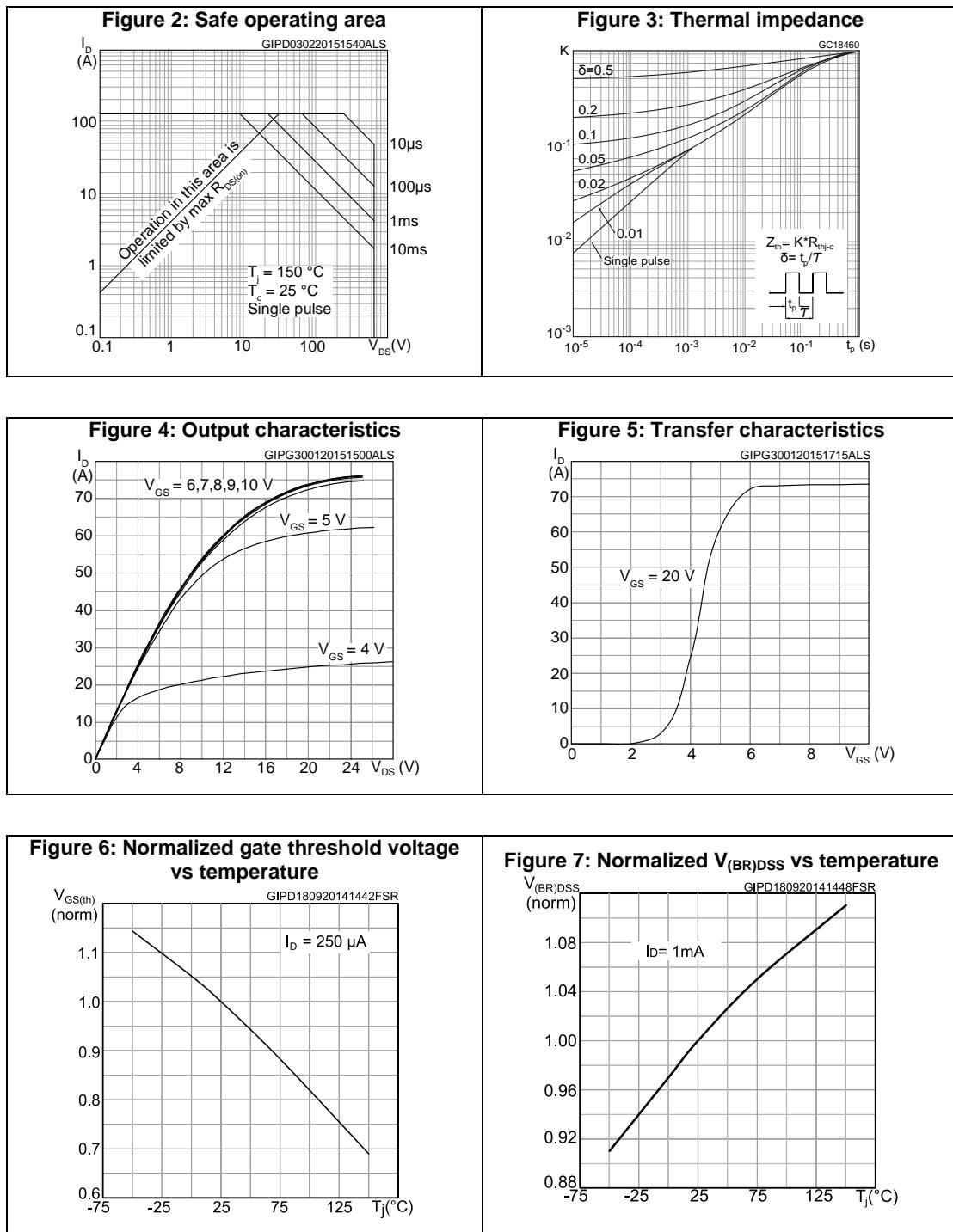
Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		32	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		128	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0 \text{ V}$ , $I_{SD} = 32 \text{ A}$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 32 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ , $V_{DD} = 60 \text{ V}$ (see <i>Figure 16: "Test circuit for inductive load switching and diode recovery times"</i> )	-	468		ns
$Q_{rr}$	Reverse recovery charge		-	8.7		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	37.5		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 32 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ , $V_{DD} = 60 \text{ V}$ , $T_j = 150^\circ\text{C}$ (see <i>Figure 16: "Test circuit for inductive load switching and diode recovery times"</i> )	-	610		ns
$Q_{rr}$	Reverse recovery charge		-	11.7		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	39		A

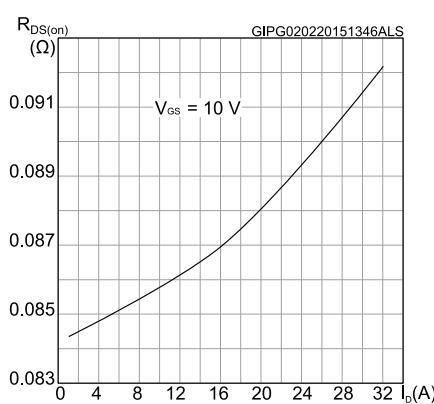
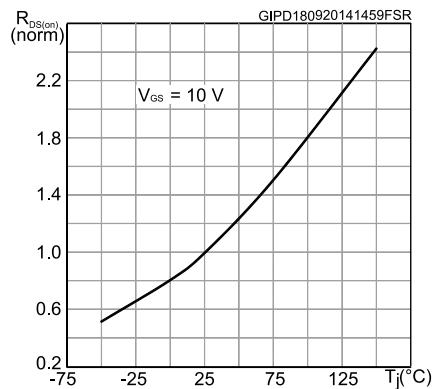
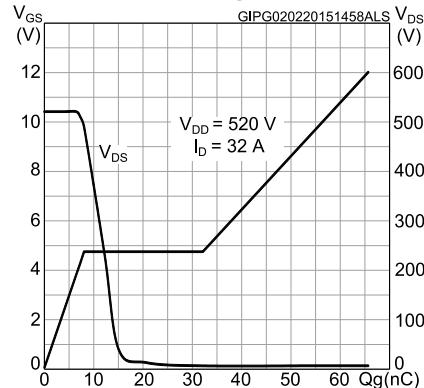
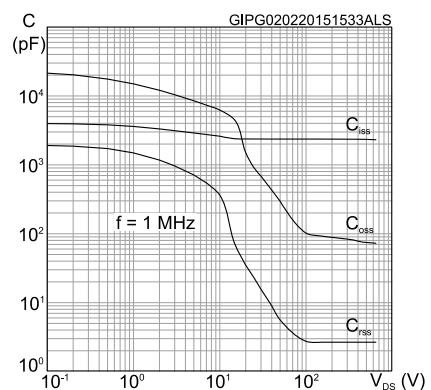
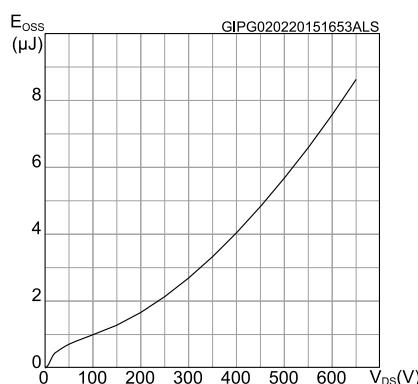
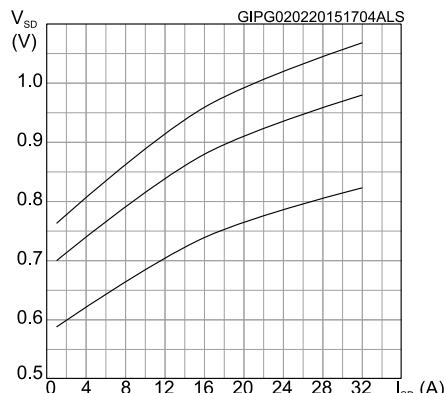
**Notes:**

(1)Pulse width is limited by safe operating area

(2)Pulse test: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

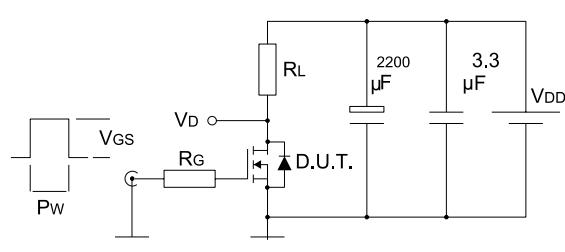
## 2.2 Electrical characteristics (curves)



**Figure 8: Static drain-source on-resistance****Figure 9: Normalized on-resistance vs. temperature****Figure 10: Gate charge vs. gate-source voltage****Figure 11: Capacitance variations****Figure 12: Output capacitance stored energy****Figure 13: Source-drain diode forward characteristics**

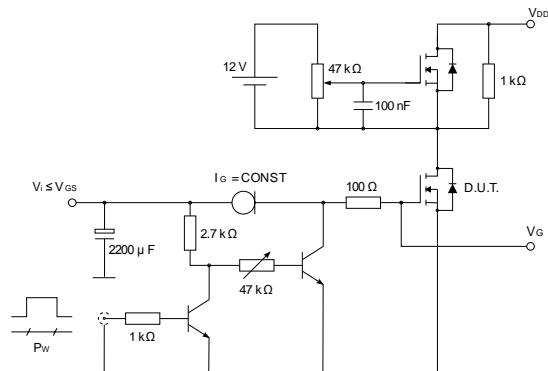
### 3 Test circuits

**Figure 14: Switching times test circuit for resistive load**



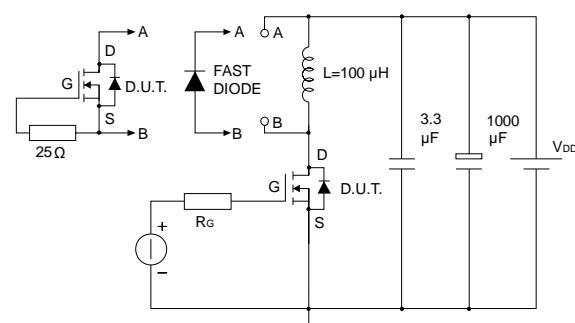
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**Figure 15: Gate charge test circuit**



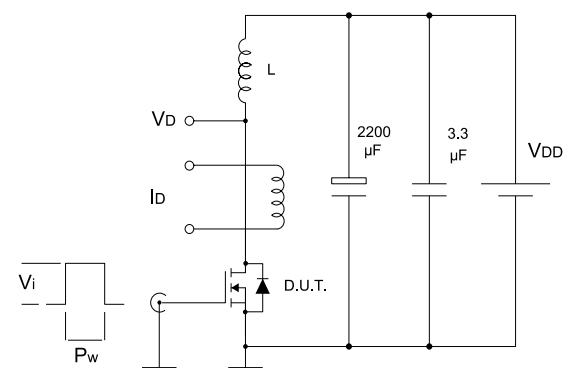
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**Figure 16: Test circuit for inductive load switching and diode recovery times**



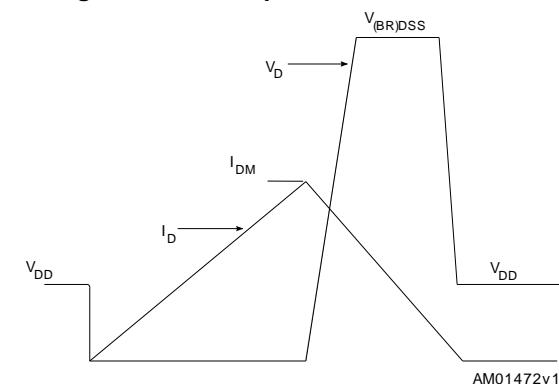
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**Figure 17: Unclamped inductive load test circuit**



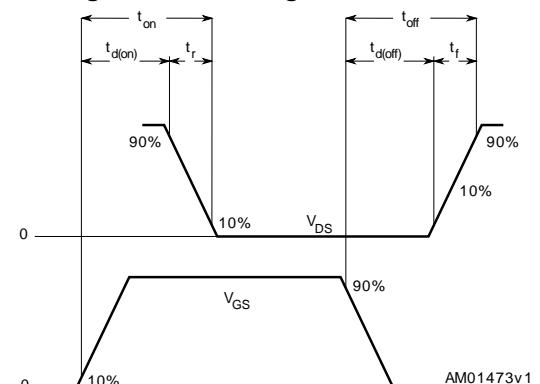
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**Figure 18: Unclamped inductive waveform**



AM01472v1

**Figure 19: Switching time waveform**



AM01473v1

## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

### 4.1 TO-247 package information

Figure 20: TO-247 drawing

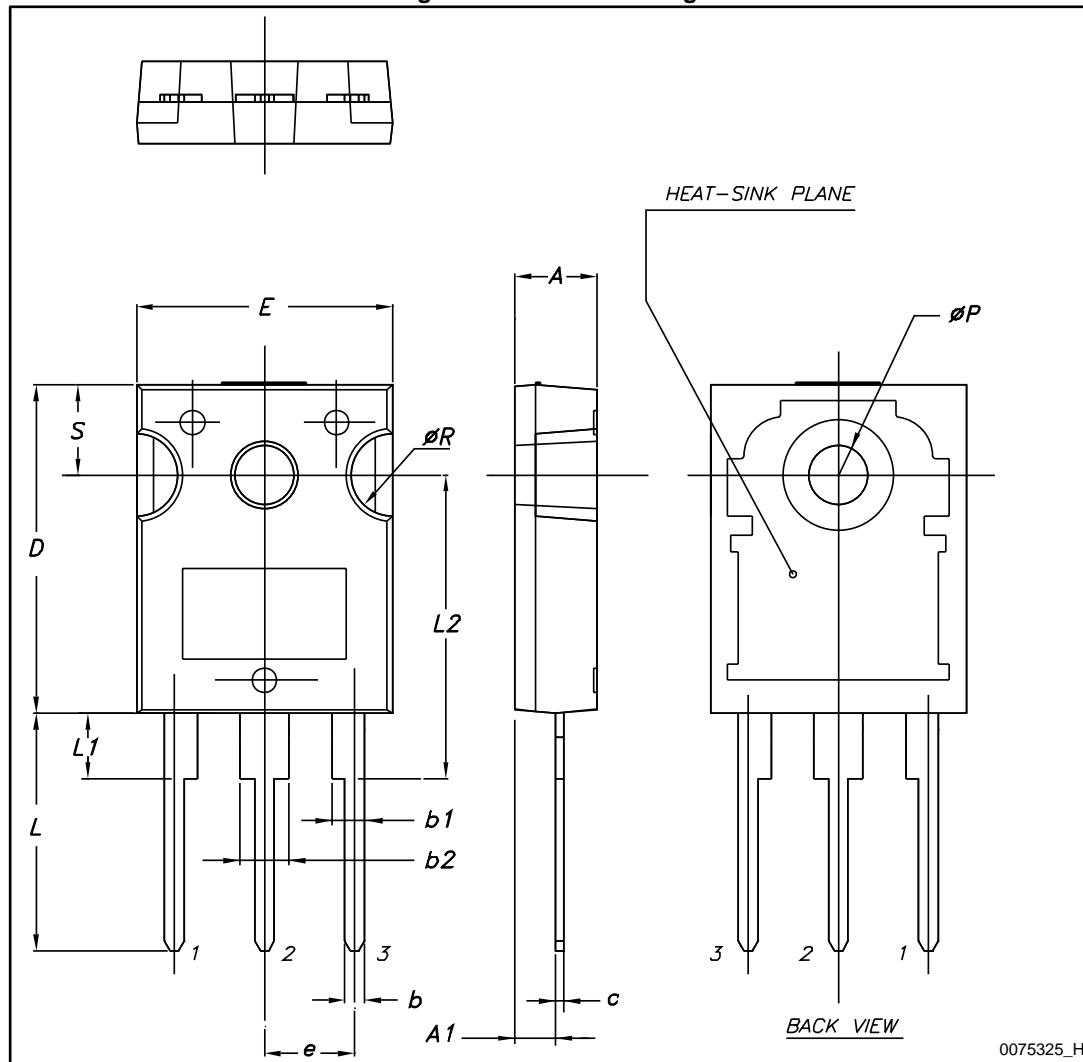


Table 9: TO-247 mechanical data

Dim.	mm.		
	Min.	Typ.	Max.
A	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
c	0.40		0.80
D	19.85		20.15
E	15.45		15.75
e	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70

## 5 Revision history

**Table 10: Document revision history**

Date	Revision	Changes
09-Feb-2014	1	First release.

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